**REVISIONS** Device 01 inactive for new design as of 30 May 1978. LTR DATE **DESCRIPTION** APPROVED Use M38510/31403B Ε Change truth table. Remove vendor 27014.Change to Military drawing 16 JUNE 1987 format. Add LCC package. REV PAGE REV Ē E Ē **REV STATUS OF PAGES PAGES** 5 **Defense Electronics Supply Center** This drawing is available for use by Dayton, Ohio CHECKED all Departments and Agencies of the Department of Defense TITLE: MICROCIRCUITS, DIGITAL, LOW POWER SCHOTTKY TTL, MULTIVIBRATOR, Original date of drawing: 19 MARCH 1976 MONOLITHIC SILICON SIZE CODE IDENT. NO. DWG NO. 76003 14933 Α AMSC N/A REV Ε PAGE OF 12 5962-E269

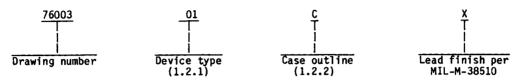
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- 1.1 Scope. This drawing describes the requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".
  - 1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type Generic number Circuit function

O1 54LS122 Single retriggerable monostable multivibrator with clear

1.2.2 <u>Case outlines</u>. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

 Outline letter
 Case outline

 C
 D-1 (14-lead, 1/4" x 3/4"), dual-in-line package

 D
 F-2 (14-lead, 1/4" x 3/8"), flat package

 2
 C-2 (20-terminal, .350" x .350"), chip carrier package

1.3 Absolute maximum ratings.

1.4 Recommended operating conditions.

Supply voltage ( $V_{CC}$ ) - - - - - - - - - - - 4.5 V dc minimum to 5.5 V dc maximum Minimum high level input voltage ( $V_{IH}$ ) - - - - - 2.0 V dc Maximum low level input voltage ( $V_{IL}$ ) - - - - - - - - - - - - - - 55°C to +125°C

- I/ Must withstand the added  $P_D$  due to short circuit test (e.g.,  $I_{OS}$ ).
- $\frac{2}{}$  When a thermal resistance for this case is specified in MIL-M-38510, appendix C, that value shall supersede the value specified herein.

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2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

**SPECIFICATION** 

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connections with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

## 3. REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
  - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
  - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.
- 3.4 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a munfacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

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	TABLE 1	. Electrical	performance char	acteristics	•		
Test	Symbol   	-55°C <	ditions T <sub>C &lt;</sub> +125°C wise specified	Group A subgroups		its   Max	<del>i Unit</del> T
High level output voltage	i v <sub>oh</sub>	V <sub>CC</sub> = 4.5 V;   I <sub>OH</sub> = -400 μA	V <sub>11</sub> = 0.7 V	1, 2, 3	2.5	]   	   V 
Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V;   I <sub>OL</sub> = 4 mA	V <sub>IH</sub> = 2.0 V	1, 2, 3		0.4	<b>V</b>
Input clamp voltage	V <sub>IC</sub>	V <sub>CC</sub> = 4.5 V;  T <sub>C</sub> = +25 °C	$I_{IN} = -18 \text{ mA}$	1		  -1.5 	٧
High level input current	I <sub>IH1</sub>	V <sub>CC</sub> = 5.5 V;	V <sub>IH</sub> = 2.7 ¥ <u>1</u> /	1, 2, 3		20	   μ <b>Α</b>
7	I <sub>IH2</sub>	V <sub>CC</sub> = 5.5 V;	V <sub>IH</sub> = 5.5 V <u>1</u> /	1, 2, 3		   100 	μ <b>Α</b>
Low level input current	IIL	V <sub>CC</sub> = 5.5 V;	V <sub>IL</sub> = 0.4 V <u>2</u> /	1, 2, 3		  -400 	μΑ
Short-circuit output current	Ios		<u>3</u> /	1, 2, 3	-15	  -150 	mA
Supply current	ICC	V <sub>CC</sub> = 5.5 V		1, 2, 3		111	l mA
Functional tests		  See 4.3.1c		7		]   	
Propagation delay time, high-to-low level 4/ A to 0		V <sub>CC</sub> = 5.0 V   R <sub>L</sub> = 2 kΩ   ±5%	 	9		   45 	ns
7 60 Y		R <sub>ext</sub> = 5 kΩ  C <sub>ext</sub> = 0	 	10, 11		   63   	ns
		]   	  C <sub>L</sub> = 50 pF ±10%  	9		   50	ns
		 	] 	10, 11		70	ns

See footnotes at end of table.

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	TABLE I. E	lectrical perf	ormance character	ristics - Co	ntinued.		
Test	Symbol	-55°C <	nditions T <sub>C</sub> < +125°C rwise specified	Group A     subgroups  	Limits Min   M	ax [	īŧ
Propagation delay time, low-to-high level 4/ A to Q	tpLH1	V <sub>CC</sub> = 5.0 V   R <sub>L</sub> = 2 kΩ   ±5%	  C <sub>L</sub> = 15 pF ±10%	9		33 n	s
·	İ	$ R_{\text{ext}} = 5 \text{ k}\Omega $ $ C_{\text{ext}} = 0$		10, 11		46   n	S
		 	C <sub>L</sub> = 50 pF ±10%	9		38   n:	s
		! 		10, 11		53 n:	5
Propagation delay time, high-to-low level $\frac{4}{\sqrt{2}}$	t <sub>PHL2</sub>	 	C <sub>L</sub> = 15 pF ±10%	9		56   ns	; 
5 to 4		 		10, 11	:	78   ns	<b>;</b>
		!   !	C <sub>L</sub> = 50 pF ±10%	9	! 	61   ns	3
	 	<u> </u> 	] 	10, 11	8	35 ns	·
ropagation delay time, low-to-high level 4/	t <sub>PLH2</sub>		  C <sub>L</sub> = 15 pF ±10%  	9	4	14 ns	
B to Q			] i   	10, 11	6	52   ns	
			  C <sub>L</sub> = 50 pF ±10%  	9	4	19 ns	
			[   	10, 11	6	9 ns	
ropagation delay time, high-to-low level <u>4</u> / clear to Q	t <sub>PHL3</sub>		C <sub>L</sub> = 15 pF ±10%	9	2	7   ns	
		   <u> </u>		10, 11	3	8   ns	
		] !	C <sub>L</sub> = 50 pF ±10%	9	] ] ]	2   ns	
	1 1		Ī	10, 11	49	5 I ns	

Test	Symbol	-55°C <	ditions T <sub>C ≤</sub> +125°C wise specified	Group A subgroups	Limits Min Max	Unit
Propagation delay time, low-to-high level 4/	t <sub>PLH3</sub>	  Y <sub>CC</sub> = 5.0 V  R <sub>L</sub> = 2 kΩ   ±5%	  C <sub>L</sub> = 15 pF ±10%  	9	45	ns ns
clear to Q		$R_{\text{ext}} = 5 \text{ k}\Omega$		10, 11	63	ns
		1 	C <sub>L</sub> = 50 pF ±10%	9	50	ns
		 	1	10, 11	70	ns
Propagation delay time, high-to-low level 4/	t <sub>WQ</sub> (MIN)	! ! !	C <sub>L</sub> = 15 pF ±10%	9	200	ns
Q from A or B	1	   	 	10, 11	280	ns
		   	  C <sub>L</sub> = 50 pF ±10%  	9	216	ns
		 	!   	10, 11	302	ns
Propagation delay time, low-to-high level <u>4</u> /	t <sub>WQ</sub>	  Y <sub>CC</sub> = 5.0 V  R <sub>L</sub> = 2 kΩ   ±5%	  C <sub>L</sub> = 15 pF ±10%	9		μs
Q from A or B		R <sub>ext</sub> = 10 kΩ  C <sub>ext</sub> =   1000 pF	;   	10, 11	7	μs

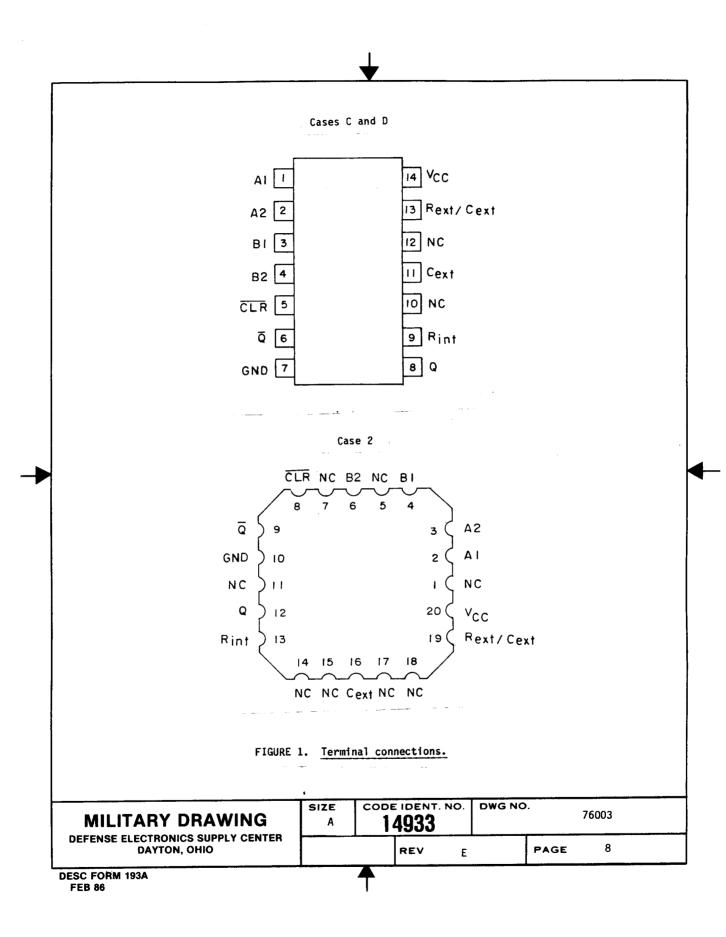
All unspecified inputs grounded.
All unspecified inputs at 5.5 volts.
Not more than one output should be shorted at a time, and the duration of the short circuit

condition should not exceed one second. Propagation delay time testing may be performed using either  $C_L = 15$  pF or  $C_L = 50$  pF. However, the manufacturer must certify and guarantee that the microcircuits meet the switching test limits specified for a 50 pF load.

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- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification of review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
  - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test (method 1015 of MIL-STD-883).
    - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
- 4.3.1 Group A inspection. Group A inspection shall consist of the test subgroups and LTPD values shown in table I of method 5005 of MIL-STD-883, class B, and as follows:
  - a. Tests shall be as specified in table II herein.
  - b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
  - c. Subgroup 7 tests sufficient to verify the truth table.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
      - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5).
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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	In	puts			Out	puts	
  Clear 	IA1	A2	В1	В2	Q	Q	
L	I X	Х	Х	χ	ļ L	Н	Ţ
х	ļн	Н	Х	X	L	Н	
Х	X	X	L	Х	   L	Н	OUTPUTS   SEE NOTE
Х	ļх	Χ	Х	L	L	Н	
н	إل	Χ	÷	Н		Ţ	
Н	L	Χ	Н	÷	1	L	
Н	X	L	<b>†</b>	Н	ļл	Ţ	
Н	x	L	н	<b>†</b>	1		
Н	Н	ţ	н	Н	ļЛ	Ţ	
н	ļ +	<b>+</b>	Н	Н		L	' 
н	+	Н	Н	Н	<u> </u>	ப	
<b>†</b>	   L	Χ	Н	Н	ן דע	Ţ	•
†	l X	L	Н	Н	177	П	

1. These lines of the functional tables assume that the indicated steady-state conditions at the A and B inputs have been set up long enough to complete any pulse started before the setup.

to complete any pulse started before the setup.

2. H = high level (steady state), L = low level (steady state), ↑ = transition from low to high level, ↓ = transition from high to low level, □ = one high-level pulse, □ = one low-level pulse, X = irrelevant (any input, including transitions).

3. To use the internal timing resistor of LS122, connect Rint to VCC.

4. An external timing capacitor may be connected between Cext and Rext/Cext (positive).

5. For accurate repeatable pulse widths, connect an external resistor between Rout/Coxt and VCC with Rint open circuited.

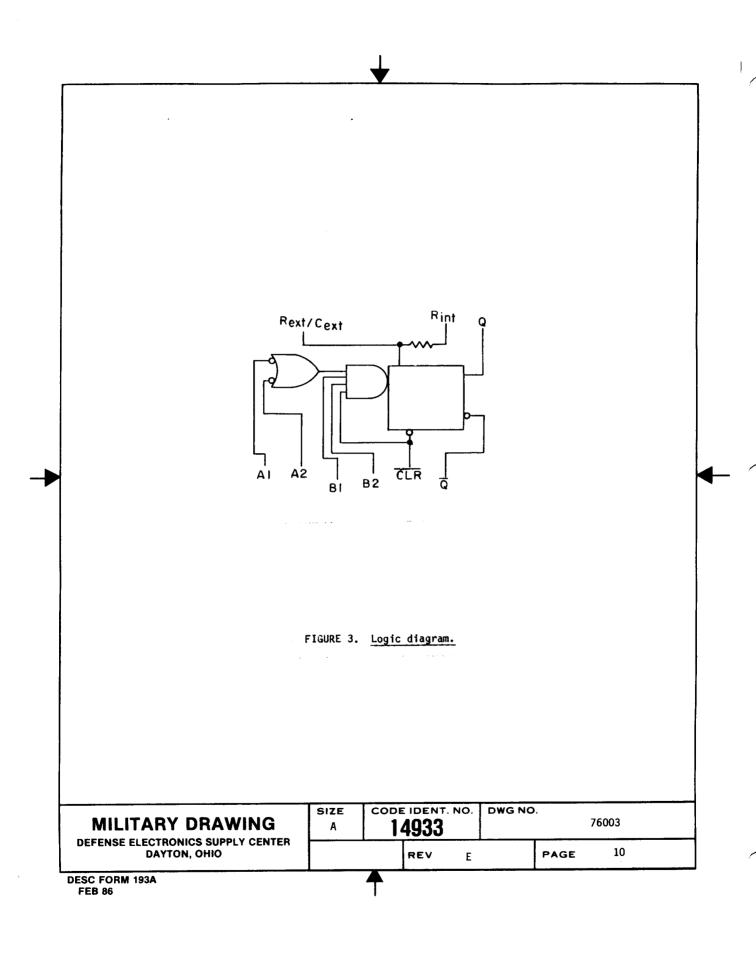
 $R_{\rm ext}/C_{\rm ext}$  and  $V_{\rm CC}$  with  $R_{\rm int}$  open circuited. To obtain variable pulse widths, connect external variable resistance between

Rint or Rext/Cext and VCC.

FIGURE 2. Truth table.

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MIL-STD-883 test requirements	Subgroups   (per method   5005, table I)
Interim electrical parameters   (method 5004) 	
Final electrical test parameters   (method 5004) 	1*, 2, 3, 9
Group A test requirements   (method 5005)	1, 2, 3, 7, 9, 110, 11**
Groups C and D end-point   electrical parameters   (method 5005) 	1, 2, 3

PDA applies to subgroup 1. Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
  - 6.2 Replaceability. Replaceability is determined as follows:
    - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
    - b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/31403B--.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, OH 45444, or telephone 513-296-5375.

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6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor   CAGE   Inumber	Similar <u>1</u> /   vendor type	Replacement  military specification    part number
7600301CX 2/	01295 04713	  SNJ54LS122J  54LS122/BCBJC	M38510/31403BCX
7600301DX <u>2</u> /	01295	SNJ54LS122W   54LS122/BDBJC	M38510/31403BDX
76003012X <u>2</u> /	01295 04713	  SNJ54LS122FK  54LS122M/B2BJC 	M38510/31403B2X

- $\frac{1}{a}$  CAUTION. Do not use this number for item acquisition. Items acquired to the similar vendor type only may not satisfy the performance requirements of this drawing.
- 2/ Inactive for new design. Use QPL-38510 product.

Vendor CAGE number	Vendor name and address	
01295	Texas Instruments, Inc. P. O. Box 6448 Midland, TX 79701	
04713	Motorola, Inc. 7402 South Price Road Tempe, AZ 85283	

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